

# Adolf Canillas

## List of Publications by Year in descending order

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64  
papers

1,517  
citations

304743

22  
h-index

330143

37  
g-index

64  
all docs

64  
docs citations

64  
times ranked

1167  
citing authors

#	ARTICLE	IF	CITATIONS
1	Spontaneous mirror-symmetry breaking coupled to top-bottom chirality transfer: from porphyrin self-assembly to scalemic Diels-Alder adducts. <i>Chemical Communications</i> , 2019, 55, 12219-12222.	4.1	18
2	Quaternion algebra for Stokes-Mueller formalism. <i>Journal of the Optical Society of America A: Optics and Image Science, and Vision</i> , 2019, 36, 492.	1.5	5
3	Hydrodynamic Effects in Soft-matter Self-assembly: The Case of Aggregates of Amphiphilic Porphyrins. <i>Chemical Record</i> , 2017, 17, 713-724.	5.8	28
4	Retrieval of the non-depolarizing components of depolarizing Mueller matrices by using symmetry conditions and least squares minimization. <i>Applied Surface Science</i> , 2017, 421, 697-701.	6.1	1
5	Mueller matrix polarimetry on a Young's double-slit experiment analog. <i>Optics Letters</i> , 2017, 42, 3900.	3.3	9
6	Relation between 2D/3D chirality and the appearance of chiroptical effects in real nanostructures. <i>Optics Express</i> , 2016, 24, 2242.	3.4	70
7	Reversible and irreversible emergence of chiroptical signals in J-aggregates of achiral 4-sulfonatophenyl substituted porphyrins: intrinsic chirality vs. chiral ordering in the solution. <i>Chemical Communications</i> , 2016, 52, 10874-10877.	4.1	15
8	Heterogeneous distribution of B-site cations in BaZrTi <sub>1-x</sub> O <sub>3</sub> epitaxial thin films grown on (001) SrTiO <sub>3</sub> by pulsed laser deposition. <i>Applied Surface Science</i> , 2016, 381, 12-16.	6.1	4
9	Optical security verification by synthesizing thin films with unique polarimetric signatures. <i>Optics Letters</i> , 2015, 40, 5399.	3.3	14
10	Mueller matrix microscopy on a Morpho butterfly. <i>Journal of Physics: Conference Series</i> , 2015, 605, 012008.	0.4	8
11	Structure vs. excitonic transitions in self-assembled porphyrin nanotubes and their effect on light absorption and scattering. <i>Nanoscale</i> , 2015, 7, 20435-20441.	5.6	17
12	Mueller matrix microscope with a dual continuous rotating compensator setup and digital demodulation. <i>Applied Optics</i> , 2014, 53, 2236.	1.8	104
13	Transmission ellipsometry of anisotropic substrates and thin films at oblique incidence. Handling multiple reflections. <i>Thin Solid Films</i> , 2014, 571, 701-705.	1.8	14
14	Achiral to Chiral Transition in Benzil Solidification: Analogies with Racemic Conglomerates Systems Showing Deracemization. <i>Chirality</i> , 2013, 25, 393-399.	2.6	10
15	Alignment and Chirality of Porphyrin J Aggregates Formed at the Liquid-Liquid Interface of a Centrifugal Liquid Membrane Cell. <i>Langmuir</i> , 2013, 29, 7249-7256.	3.5	13
16	Kinetic Control of the Supramolecular Chirality of Porphyrin Aggregates. <i>Chemistry - A European Journal</i> , 2012, 18, 8820-8826.	3.3	35
17	Flow Effects in Supramolecular Chirality. <i>Israel Journal of Chemistry</i> , 2011, 51, 1007-1016.	2.3	23
18	Chirality generated by flows in pseudocyanine dye aggregates: Revisiting 40 years old reports. <i>Chirality</i> , 2011, 23, 585-592.	2.6	22

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19	Transmission Mueller matrix ellipsometry of chirality switching phenomena. <i>Thin Solid Films</i> , 2011, 519, 2617-2623.	1.8	14
20	Detection and characterization of single nanoparticles by interferometric phase modulated ellipsometry. <i>Thin Solid Films</i> , 2011, 519, 2801-2805.	1.8	2
21	Measurement of the optical activity of anisotropic samples by transmission Mueller matrix ellipsometry. <i>EPJ Web of Conferences</i> , 2010, 5, 03001.	0.3	9
22	Chiral Biases in Solids by Effect of Shear Gradients: A Speculation on the Deterministic Origin of Biological Homochirality. <i>Origins of Life and Evolution of Biospheres</i> , 2010, 40, 27-40.	1.9	12
23	Emergence of Supramolecular Chirality by Flows. <i>ChemPhysChem</i> , 2010, 11, 3511-3516.	2.1	66
24	Analytic inversion of the Mueller-Jones polarization matrices for homogeneous media. <i>Optics Letters</i> , 2010, 35, 559.	3.3	104
25	Analytic inversion of the Mueller-Jones polarization matrices for homogeneous media: erratum. <i>Optics Letters</i> , 2010, 35, 3525.	3.3	14
26	Chiral sign selection on the aggregates of diprotonated tetrakis(4-sulfonatophenyl)porphyrin by traces of unidentified chiral contaminants present in the ultra-pure water used as solvent. <i>Chirality</i> , 2009, 21, 408-412.	2.6	62
27	Reversible Mechanical Induction of Optical Activity in Solutions of Soft Matter Nanophases. <i>Chemistry - an Asian Journal</i> , 2009, 4, 1687-1696.	3.3	34
28	Evidence of induced chirality in stirred solutions of supramolecular nanofibers. <i>Optics Letters</i> , 2009, 34, 2177.	3.3	50
29	Pseudopolar decomposition of the Jones and Mueller-Jones exponential polarization matrices. <i>Journal of the Optical Society of America A: Optics and Image Science, and Vision</i> , 2009, 26, 783.	1.5	53
30	Determination of the components of the gyration tensor of quartz by oblique incidence transmission two-modulator generalized ellipsometry. <i>Applied Optics</i> , 2009, 48, 5307.	2.1	44
31	Application of transmission ellipsometry to the determination of CD spectra of porphyrin aggregates solid-state samples. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2008, 205, 797-801.	1.8	8
32	Optical characterization of colloidal crystals based on dissymmetric metal-coated oxide submicrospheres. <i>Thin Solid Films</i> , 2008, 517, 1053-1057.	1.8	8
33	On the Mechano-Chiral Effect of Vortical Flows on the Dichroic Spectra of 5-Phenyl-10,15,20-tris(4-sulfonatophenyl)porphyrin Aggregates. <i>Chemistry - A European Journal</i> , 2008, 14, 6438-6443.	1.3	56
34	Optical characterization of ns-SiN:H in the infrared by spectroscopic ellipsometry. <i>Applied Surface Science</i> , 2006, 253, 65-69.	6.1	3
35	FTIR phase-modulated ellipsometry characterization of hydrogenated amorphous silicon nitride thin films with embedded nanoparticles. <i>Thin Solid Films</i> , 2004, 455-456, 167-171.	1.8	3
36	Visible and infrared ellipsometry applied to the study of metal-containing diamond-like carbon coatings. <i>Thin Solid Films</i> , 2004, 455-456, 370-375.	1.8	7

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37	Study of the oxidization of ns-SiNx:H thin films using FTIR phase modulated ellipsometry. , 2004, , .		1
38	Application of FTIR phase-modulated ellipsometry to the characterisation of thin films on surface-enhanced IR absorption active substrates. Thin Solid Films, 2001, 398-399, 99-103.	1.8	5
39	Spectroscopic ellipsometric study of tetrahedral amorphous carbon films: optical properties and modelling. Diamond and Related Materials, 2001, 10, 1132-1136.	3.9	27
40	Effective dielectric function of mixtures of three or more materials: a numerical procedure for computations. Surface Science, 2000, 453, 9-17.	1.9	79
41	Optimized calibration method for Fourier transform infrared phase-modulated ellipsometry. Thin Solid Films, 1999, 354, 187-194.	1.8	10
42	Numerical algorithm for spectroscopic ellipsometry of thick transparent films. Applied Optics, 1998, 37, 1177.	2.1	11
43	Calibration improvement of Fourier transform infrared phase-modulated ellipsometry. Journal of the Optical Society of America A: Optics and Image Science, and Vision, 1996, 13, 2461.	1.5	5
44	Effects of plasma processing on the microstructural properties of silicon powders. Plasma Sources Science and Technology, 1994, 3, 348-354.	3.1	33
45	Optical, vibrational and compositional study of amorphous silicon oxynitride thin films grown by an RF plasma using N2O + SiH4 gas mixtures. Applied Surface Science, 1993, 70-71, 695-700.	6.1	9
46	An IR phase-modulated ellipsometer using a Fourier transform spectrometer for in situ applications. Thin Solid Films, 1993, 234, 318-322.	1.8	18
47	Effect of hydrogen dilution on the growth of hydrogenated amorphous silicon studied by in-situ phase-modulated ellipsometry. Thin Solid Films, 1993, 228, 109-112.	1.8	8
48	In situ real-time ellipsometric study of the growth of r.f. plasma deposited amorphous hydrogenated silicon oxynitride thin films. Thin Solid Films, 1993, 228, 137-140.	1.8	3
49	Effects of r.f. power on optical and electrical properties of plasma-deposited hydrogenated amorphous silicon thin films. Sensors and Actuators A: Physical, 1993, 37-38, 733-736.	4.1	2
50	Plasma-deposited silicon nitride films with low hydrogen content for amorphous silicon thin-film transistors application. Sensors and Actuators A: Physical, 1993, 37-38, 333-336.	4.1	10
51	Study of thin films of transparent electronic materials by phase-modulated spectroellipsometry. Thin Solid Films, 1993, 233, 223-226.	1.8	1
52	Error minimization method for spectroscopic and phase-modulated ellipsometric measurements on highly transparent thin films. Journal of the Optical Society of America A: Optics and Image Science, and Vision, 1993, 10, 713.	1.5	11
53	Phase-modulated ellipsometer using a Fourier transform infrared spectrometer for real time applications. Review of Scientific Instruments, 1993, 64, 2153-2159.	1.3	57
54	Properties of amorphous silicon thin films grown in square wave modulated silane rf discharges. Journal of Applied Physics, 1992, 71, 1546-1548.	2.5	15

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55	Optical and electrical properties of a-Si <sub>x</sub> N <sub>y</sub> :H films prepared by rf plasma using N <sub>2</sub> +SiH <sub>4</sub> gas mixtures. Journal of Non-Crystalline Solids, 1991, 137-138, 895-898.	3.1	7
56	Surface roughness evolution in the growth of a-Si: H thin films studied by ellipsometry. Surface Science, 1991, 251-252, 191-194.	1.9	3
57	Ellipsometric study of a-Si:H thin films deposited by square wave modulated rf glow discharge. Journal of Applied Physics, 1991, 69, 632-638.	2.5	39
58	Effects of deposition temperature on properties of r.f. glow discharge amorphous silicon thin films. Thin Solid Films, 1991, 205, 140-145.	1.8	7
59	Influence of pressure and radio frequency power on deposition rate and structural properties of hydrogenated amorphous silicon thin films prepared by plasma deposition. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1991, 9, 2216-2221.	2.1	52
60	Effect of substrate temperature on deposition rate of rf plasma-deposited hydrogenated amorphous silicon thin films. Journal of Applied Physics, 1991, 69, 3757-3759.	2.5	13
61	In situ spectroellipsometric study of the nucleation and growth of amorphous silicon. Journal of Applied Physics, 1990, 68, 2752-2759.	2.5	68
62	In situ optical characterizations for rf plasma deposited a-Si: H thin films. Vacuum, 1989, 39, 785-787.	3.5	30
63	Real time controlled rf reactor for deposition of a-Si:H thin films. Vacuum, 1989, 39, 795-798.	3.5	34
64	Deposition of amorphous silicon films from an electrostatically confined silane plasma. Vacuum, 1987, 37, 443-444.	3.5	0